

**Search Notes**

Application/Control No.

10/764,999

Examiner

Ryan Lepisto

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2883

**SEARCHED**

Class	Subclass	Date	Examiner
385	75	8/15/2006	RAL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
385	75	8/15/2006	RAL
See interference search printouts		8/15/2006	RAL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See search printouts - EAST (all databases), PALM (inventorship), non- patent literature (IEEE, INSPEC)	8/15/2006	RAL
Consulted Frank Font on allowability <i>FJF</i>	8/15/06	RAL